

10073830_CLS
Most Frequently Occurring Classifications of Patents Returned
From A Search of 10073830 on June 30, 2004

Original Classifications

11	714/727
6	714/726
3	324/158.1
3	714/724
2	324/763
2	326/38
2	703/14
2	714/731
2	714/733
2	717/139

Cross-Reference Classifications

9	714/727
7	714/724
4	714/30
4	714/731
4	714/733
3	324/158.1
3	714/725
3	714/726
3	716/4
2	326/40
2	326/41
2	326/46
2	703/13
2	714/42
2	714/734
2	716/1
2	716/16
2	716/17

Combined Classifications

20	714/727
10	714/724
9	714/726
6	324/158.1
6	714/731
6	714/733
5	714/30
3	326/38
3	703/14
3	714/725
3	716/16

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3 716/4
2 324/763
2 326/39
2 326/40
2 326/41
2 326/46
2 327/202
2 365/201
2 703/13
2 714/42
2 714/734
2 716/1
2 716/17
2 717/139

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Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 10073830 on June 30, 2004

20	714/727	(11 OR, 9 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/726	..Scan path testing (e.g., level sensitive scan design (LSSD))
	714/727	...Boundary scan
10	714/724	(3 OR, 7 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
9	714/726	(6 OR, 3 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/726	..Scan path testing (e.g., level sensitive scan design (LSSD))
6	324/158.1	(3 OR, 3 XR)
	Class 324 :	ELECTRICITY: MEASURING AND TESTING
	324/158.1	MISCELLANEOUS
6	714/731	(2 OR, 4 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/726	..Scan path testing (e.g., level sensitive scan design (LSSD))
	714/731	...Clock or synchronization
6	714/733	(2 OR, 4 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING

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714/724 .Digital logic testing
714/733 ..Built-in testing circuit (BILBO)

5 714/30 (1 OR, 4 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

714/1 .Reliability and availability

714/25 ..Fault locating (i.e., diagnosis or testing)

714/27 ...Particular access structure

714/30Built-in hardware for diagnosing or testin

g
or test mode
within-system component (e.g., microprocess
circuit, scan path)

3 326/38 (2 OR, 1 XR)

Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G.,
UNIVERSAL, ETC.)

326/38 .Having details of setting or programming of
interconnections or logic functions

3 703/14 (2 OR, 1 XR)

Class 703 : DATA PROCESSING: STRUCTURAL DESIGN,
MODELING, SIMULATION, AND EMULATION
703/13 SIMULATING ELECTRONIC DEVICE OR ELECTRICAL
SYSTEM

703/14 .Circuit simulation

3 714/725 (0 OR, 3 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

714/725 ..Programmable logic array (PLA) testing

3 716/16 (1 OR, 2 XR)

Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
CIRCUIT OR SEMICONDUCTOR MASK

716/1 CIRCUIT DESIGN

716/12 .Routing (e.g., routing map, netlisting)

716/16 ..PLA, PLD, FPGA, OR MCM

3 716/4 (0 OR, 3 XR)

Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF

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CIRCUIT OR SEMICONDUCTOR MASK
CIRCUIT DESIGN
.Testing or evaluating

- 716/1
716/4
- 2 324/763 (2 OR, 0 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
ELECTRIC COMPONENTS
324/537 .Of individual circuit component or element
324/763 ..DUT including test circuit
- 2 326/39 (1 OR, 1 XR)
Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G.,
UNIVERSAL, ETC.)
326/39 .Array (e.g., PLA, PAL, PLD, etc.)
- 2 326/40 (0 OR, 2 XR)
Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G.,
UNIVERSAL, ETC.)
326/39 .Array (e.g., PLA, PAL, PLD, etc.)
326/40 ..With flip-flop or sequential device
- 2 326/41 (0 OR, 2 XR)
Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G.,
UNIVERSAL, ETC.)
326/39 .Array (e.g., PLA, PAL, PLD, etc.)
326/41 ..Significant integrated structure, layout, or
layout interconnections
- 2 326/46 (0 OR, 2 XR)
Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G.,
UNIVERSAL, ETC.)
326/46 .Sequential (i.e., finite state machine) or
with flip-flop
- 2 327/202 (1 OR, 1 XR)
Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
DEVICES, CIRCUITS, AND SYSTEMS
327/100 SIGNAL CONVERTING, SHAPING, OR GENERATING
327/185 .Particular stable state circuit (e.g.,
tristable, etc.)
327/199 ..Circuit having only two stable states (i.e.,
bistable)
327/202 ...Master-slave bistable latch

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2  365/201      (1 OR, 1 XR)
    Class 365 :  STATIC INFORMATION STORAGE AND RETRIEVAL
    365/189.01  READ/WRITE CIRCUIT
    365/201     .Testing

2  703/13       (0 OR, 2 XR)
    Class 703 :  DATA PROCESSING:  STRUCTURAL DESIGN,
    703/13     MODELING, SIMULATION, AND EMULATION
    SIMULATING ELECTRONIC DEVICE OR ELECTRICAL
    SYSTEM

2  714/42       (0 OR, 2 XR)
    Class 714 :  ERROR DETECTION/CORRECTION AND FAULT
    714/100    DETECTION/RECOVERY
    DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

    714/1      .Reliability and availability
    714/25     ..Fault locating (i.e., diagnosis or testing)

    714/40     ...Component dependent technique
    714/42     ....Memory or storage device component fault

2  714/734      (0 OR, 2 XR)
    Class 714 :  ERROR DETECTION/CORRECTION AND FAULT
    714/699    DETECTION/RECOVERY
    PULSE OR DATA ERROR HANDLING
    714/724    .Digital logic testing
    714/734    ..Structural (in-circuit test)

2  716/1        (0 OR, 2 XR)
    Class 716 :  DATA PROCESSING:  DESIGN AND ANALYSIS OF
    716/1      CIRCUIT OR SEMICONDUCTOR MASK
    CIRCUIT DESIGN

2  716/17       (0 OR, 2 XR)
    Class 716 :  DATA PROCESSING:  DESIGN AND ANALYSIS OF
    716/1      CIRCUIT OR SEMICONDUCTOR MASK
    CIRCUIT DESIGN
    716/17     .Programmable integrated circuit (e.g., basic
    cell, standard cell, macrocell)

2  717/139      (2 OR, 0 XR)
    Class 717 :  DATA PROCESSING:  SOFTWARE DEVELOPMENT,
    717/100    INSTALLATION, AND MANAGEMENT
    SOFTWARE PROGRAM DEVELOPMENT TOOL (E.G.,
    INTEGRATED CASE TOOL OR STAND-ALONE DEVEL
    OPMENT TOOL)

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717/136	.Translation of code
717/139	..Interpreter

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PLUS Search Results for S/N 10073830, Searched June 30, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

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